

Monolithic Video A/D Converter

8-bit, 20MSPS

The TDC1007 is an 8-bit fully parallel (flash) analog-to-digital converter, capable of digitizing an input signal at rates up to 20MSPS (MegaSamples Per Second). It will operate accurately without the use of an external sample-and-hold amplifier, with analog input signals having frequency components up to 7MHz.

A single CONVert (CONV) signal controls the conversion operation of the device which consists of 255 sampling comparators, encoding logic, and a latched output buffer register. The device will recover from a full-scale input step in 20ns. Control inputs are provided to format the output in binary, two's complement, or inverse data coding formats.

The TDC1007 is patented under U.S. Patent No. 3283170 with other patents pending.

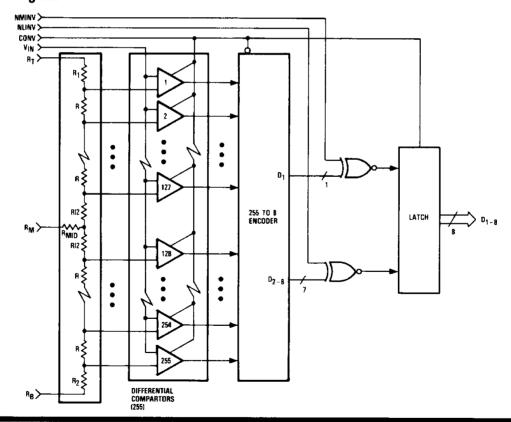
Features

- 8-Bit Resolution
- Conversion Rates Up to 20MSPS
- Sample-And-Hold Amplifier Not Required
- Bipolar Monolithic Construction
- TTL Compatible Inputs and Outputs
- Binary or Two's Complement Mode
- Differential Phase = 1.0 Degrees
- Differential Gain = 1.7%
- Evaluation Boards Available: TDC1007E1C or TDC1007P1C

Applications

- Video Systems 3x or 4x Subcarrier, NTSC or PAL
- Radar Systems
- High-Speed Multiplexed Data Acquisition
- Digital Signal Processing

Functional Block Diagram

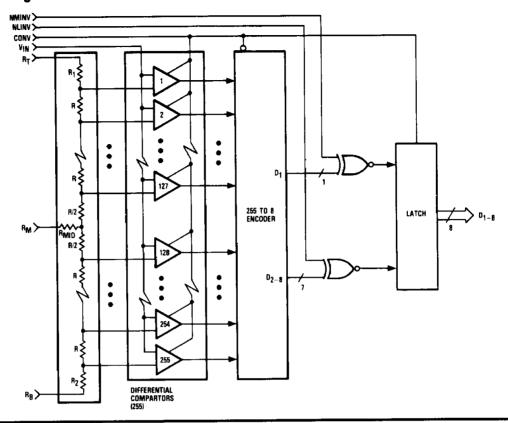


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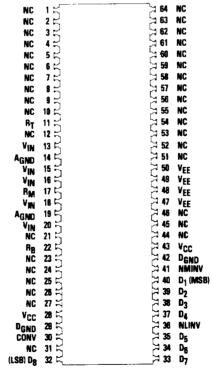
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Functional Block Diagram

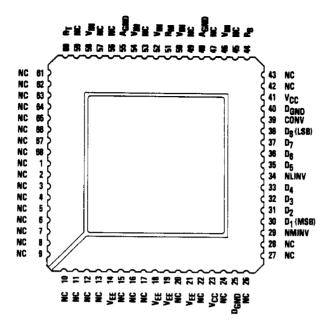


Pin Assignments



64 Lead DIP - J1 Package

Pin Assignments



68 Contact Or Leaded Chip Carrier - C1, L1 Package

Functional Description

General Information

The TDC1007 has three major functional sections: a comparator array, encoding logic, and output data latches. The input voltage is compared with 255 separate reference voltage points tapped from the reference resistor chain. The 255 comparator outputs form a code (sometimes referred to as a "thermometer" code, as all the comparators referred to voltages more positive than the input signal will be off, and

those referred to voltages more negative than the input signal will be on). The "thermometer" code from the comparator array is encoded into an eight—bit binary word by the encoding logic section. Each of these eight results is sent through an exclusive—OR gate where they are inverted by use of the NMINV or NLINV inputs. This allows operation in binary, two's complement, or inverted data formats.

Power

The TDC1007 operates from two supply voltages, +5.0V and -6.0V. The return for I_{CC}, the current drawn from the +5.0V supply, is D_{GND}. The return path for I_{EE}, the current drawn

from the $-6.0\mathrm{V}$ supply, is AGND. All power and ground pins must be connected.

Name	Function	Value	C1, L1 Package	J1 Package		
V _{CC}	Positive Supply Voltage	+5.0V	Pins 23, 41	Pins 28, 43		
VEE	Negative Supply Voltage	-6. 0V	Pins 14, 18, 19, 21	Pins 47, 48, 49, 50		
D _{GND}	Digital Ground	0.0V	Pins 25, 40	Pins 29, 42		
AGND	Analog Ground	0.0V	Pins 48, 55	Pins 14, 19		

[D]



Reference

The TDC1007 converts analog signals in the range $V_{RB} \leq V_{IN} \leq V_{RT}$ into digital form. V_{RT} (the voltage applied to the pin at the top of the reference resistor chain), and V_{RB} (the voltage applied to the pin at the bottom of the reference resistor chain) should be between +0.1V and -2.1V, with the difference between them less than 2.1V. V_{RT} should be more positive than V_{RB} within that range. In order to insure optimum operation of the TDC1007, these points should be driven by low-impedance sources capable of providing the

necessary reference resistor chain current. The voltages on R_T and R_B may be varied dynamically up to 7MHz. Due to variations in reference current with clock and input signals, R_T and R_B should be low-impedance-to-ground points. For circuits in which the reference is not varied, a bypass capacitor to ground is recommended. If the reference inputs are varied dynamically (as in an AGC application) a low-impedance reference source is required.

Name Function		Value	C1, L1 Package	J1 Package	
R _T	Reference Resistor (Top)	0.0V	Pin 60	Pin 11	
RM	Reference Resistor (Middle)	- 1.0V	Pin 51	Pin 17	
R _B	Reference Resistor (Bottom)	-2.0V	Pin 44	Pin 22	

Control

Two control inputs are provided on the TDC1007 for changing the format of the output data. When NMINV is tied to a logic "0", the most significant bit of the output data is inverted; when NLINV is tied to a logic "0", the seven least significant bits of the output are inverted. By using these controls, the

output data format can be binary, inverted binary, two's complement, or inverted two's complement. Output data versus input voltage and control input state is illustrated in the Output Coding table.

Name	Function	Value	C1, L1 Package	J1 Package
NMINV	Not Most Significant Bit INVert	TTL	Pin 29	Pin 41
NLINV	Not Least Significant Bit INVert	ΠL	Pin 34	Pin 36

Convert

The analog input to the TDC1007 is sampled (comparators are latched) approximately 10ns after the rising edge of the CONV Signal. This time delay is the sampling time offset (t_{STO}) and varies only by a few nanoseconds from device to device and as a function of temperature. The short-term uncertainty (jitter) in sampling time offset is approximately 30 picoseconds.

The output data is encoded from the 255 comparators on the falling edge of the CONV signal. The coded result is transferred to the output latches on the next rising edge of the CONV signal. Note that there are minimum pulse width (tpwH, tpwL) requirements on the waveshape of the CONV signal.

Name	Function	Value	C1, L1 Package	J1 Package	
CONV	Convert	TTL	Pin 39	Pin 30	

The input impedance of the TDC1007 varies with input signal level. As the signal varies, the comparator input transistors change from active to cut—off, causing the net input resistance and capacitance to change. To prevent this action from degrading the integrity or accuracy of the output data, it is desirable to drive the TDC1007 inputs from a low—impedance source (less than 25 Ohms). The input signal level should remain within the range of VEE to +0.5V in order to prevent damage to the device. When the input is at a level between VRT and VRB reference voltages, the output data value will be

signal. When the analog input is beyond the range of the reference voltage, the output data will be the appropriate full—scale value. Note that there are two components to the input bias current flowing into the V_{IN} pins. One component is constant for constant input voltage and is the sum of the bias currents of the subset of comparators that are active (ICB). The other component is related to the action of the CONV signal on the comparator chain (ISB). All analog input pins of the TDC1007 must be used in order to insure operation over the full input range.

Name	Function	Value	C1, L1 Package	J1 Package
VIN	Analog Input Signal	0V to −2V	Pins 46, 50, 52, 54, 58	Pins 13, 15, 16, 18, 20

Outputs

The outputs of the TDC1007 are TTL compatible and capable of driving four low-power Schottky unit loads (54/74 LS). The outputs hold the previous data a minimum time (t_{HO}) after the

directly proportional to the amplitude of the analog input

rising edge of the CONV signal, and the new data becomes valid after a maximum time of tp. For optimum performance, 2.2 kOhm pull—up resistors are recommended.

	110			
Name	Function	Value	C1, L1 Package	J1 Package
D ₁	MSB Output	ΠL	Pin 30	Pin 40
D ₂		ΠTL	Pin 31	Pin 39
03		ΠL	Pin 32	Pin 38
D ₄		πι	Pin 33	Pin 37
D ₅		TTL	Pin 35	Pin 35
06		ΠL	Pin 36	Pin 34
D ₇		πL	Pin 37	Pin 33
D ₈	LSB Output	TTL	Pin 38	Pin 32

No Connects

There are several pins labeled No Connect (NC), which have no connections to the chip. These pins may be left open.

Name	Function	Value	C1, L1 Package	J1 Package
NC	No Connect	Open	Pins 1-13, 15-17, 20, 22, 24,	Pins 1-10, 12, 24-27,
			26-28, 42, 43, 45, 47, 49, 53,	31, 44-46, 51-64
			56, 57, 59, 61, 62-68	

Figure 1. Timing Diagram

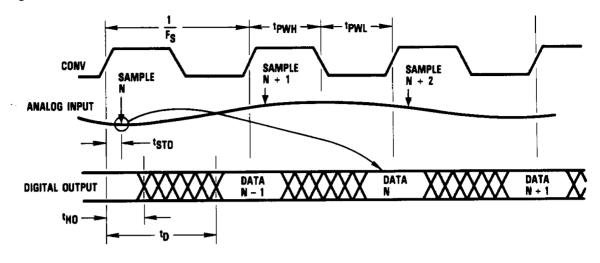
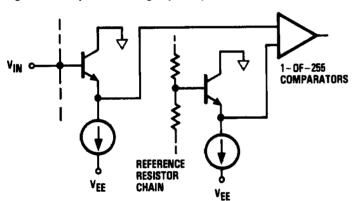
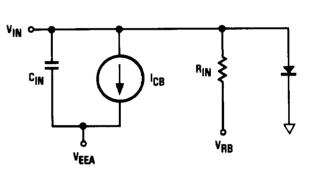


Figure 2. Simplified Analog Input Equivalent Circuit





 c_{IN} is a nonlinear junction capacitance v_{RB} is a voltage equal to the voltage on Pin \mathbf{R}_B

Figure 4. Output Circuits Figure 3. Digital Input Equivalent Circuit +Vcc ACC VCC . 810 Ω 10K **380** Ω 5K TO OUTPUT PIN INPUT O 1N3062 OUTPUT 40pF LOAD 1 = TEST LOAD FOR DELAY MEASUREMENTS OUTPUT EQUIVALENT CIRCUIT

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Absolute maximum ratings (beyond which the device will be damaged) 1

Supply Voltag	185
	V _{CC} (measured to D _{GND})
	V _{EE} (measured to A _{GND})+0.5 to -7.0V
	AGND (measured to DGND)
Input Voltage	
	CONV, NMINV, NLINV (measured to DGND)
	V _{IN} , V _{RT} , V _{RB} (measured to A _{GND})
	CONV, NMINV, NLINV (measured to DGND) -0.5 to +5.5V V _{IN} , V _{RT} , V _{R8} (measured to AGND) +0.5 to V _{EE} V V _{RT} (measured to V _{RB}) +2.2 to -2.2V
Output	
	Applied voltage (measured to D _{GND})
	Applied voltage (measured to D _{GND})
	Short circuit duration (single output in high state to ground)
Temperature	
	Operating, ambient
	junction
	Lead, soldering (10 seconds)
	Storage

Notes:

- Absolute maximum ratings are limiting values applied individually while all other parameters are within specified operating conditions.
 Functional operation under any of these conditions is NOT implied.
- 2. Applied voltage must be current limited to specified range.
- 3. Forcing voltage must be limited to specified range.
- 4. Current is specified as positive when flowing into the device.

Operating conditions

				Tempera	ture Range	•		
		Standard			Extended			1
Paramete	EE Negative Supply Voltage (Measured to AGND) AGND Analog Ground Voltage (Measured to DGND) PWL CONV Pulse Width, LOW CONV Pulse Width, HIGH IL Input Voltage, Logic LOW		Nom	Max	Min	Nom	Max	Units
VCC	Positive Supply Voltage (Measured to DGND)	4.75	5.0	5.25	4.5	5.0	5.5	٧
VEE	Negative Supply Voltage (Measured to AGND)	-5.75	-6.0	-6.25	-5.75	-6.0	-6.25	٧
VAGND	Analog Ground Voltage (Measured to DGND)	-0.1	0.0	0.1	-0.1	0.0	0.1	٧
^t PWL	CONV Pulse Width, LOW	25			25			ns
^t PWH	CONV Pulse Width, HIGH	15			15	-	-	ns
VIL	Input Voltage, Logic LOW			0.8			0.8	٧
VIH	Input Voltage, Logic HIGH	2.0			2.0		-	٧
OL	Output Current, Lagic LOW			4.0			4.0	mΑ
ОН	Output Current, Logic HIGH			-400		•	-400	μΑ
V _{RT}	Most Positive Reference Input ¹	-1.1	0.0	0.1	-1.1	0.0	0.1	ν
V _{RB}	Most Negative Reference Input	-0.9	-2.0	-2.1	-0.9	- 2.0	-2.1	V
V _{RT} -V _{RB}	Voltage Reference Differential	1.0	2.0	2.2	1.0	2.0	2.2	T v
V _{IN}	Input Voltage	V _{RT}		V _{RB}	V _{RT}		V _{RB}	٧
TA	Ambient Temperature, Still Air	0		70				°C
T _C	Case Temperature				-55		125	°C

Note:

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^{1.} $V_{\mbox{RT}}$ must be more positive than $V_{\mbox{RB}}$, and voltage reference differential must be within specified range.



Electrical characteristics within specified operating conditions

				Temperati	ire Range		
			Stan	dard	Exte	nded	
Parameter		Test Conditions	Min	Max	Min	Max	Units
lcc	Positive Supply Current	V _{CC} - MAX, Static ¹		30		35	mA
I _{EE}	Negative Supply Current	V _{EE} - MAX, Static ¹					
		T _A - 0°C to 70°C		-400			mA
	Į	T _A = 70°C		-350			mA
	i	T _C = -55°C to 125°C				-470	mA
		T _C - 125°C	<u> </u>			-320	mA
REF	Reference Current	V _{RT} , V _{RB} - NOM		35		40	mA
RREF	Total Reference Resistance		57		50		Ohms
R _{IN}	Input Equivalent Resistance	V _{RT} , V _{RB} - NOM, V _{IN} - V _{RB}	5		5		kOhms
CIN	Input Capacitance			250		250	pF
I _{CB}	Input Constant Bias Current	V _{EE} - MAX		400		500	μА
Ī _{SB}	Input Clock Synchronous Bias			200		200	μА
ī _{lL}	Input Current, Logic LOW	V _{CC} - MAX, V ₁ - 0.5V		-2.0		-2.0	mA
I _{IH}	Input Current, Logic HIGH	V _{CC} - MAX, V _I - 2.4V		75		75	μΑ
///	Input Current, Max Input Voltage	V _{CC} - MAX, V _I - 5.5V		1.0		1.0	mA
VOL	Output Voltage, Logic LOW	V _{CC} - MIN, I _{DL} - MAX		0.5		0.5	٧
VOH	Output Voltage, Logic HIGH	·	2.4		2.4		٧
los	Short Circuit Output Current	V _{CC} = MAX, Output HIGH, one pin to ground, one second duration.		-25		- 25	mA
c _l	Digital Input Capacitance	T _A = 25°C, F = 1MHz		15		15	pF

Note:

Switching characteristics within specified operating conditions

				Temperature Range				
			Star	ndard	Exte	ended		
Paran	neter	Test Conditions	Min	Max	Min	Max	Units	
FS	Maximum Conversion Rate	V _{CC} - MIN; V _{EE} - MIN	20		20		MSPS	
tst0	Sampling Time Offset	V _{CC} - MIN, V _{EE} - MIN	0	10	0	10	ПS	
t _D	Output Delay Time	V _{CC} - MIN, V _{EE} - MIN, Load 1		40		45	ns	
<u></u> -	Output Hold Time	V _{CC} - MIN, V _{EE} - MIN, Load 1	10		10		ns	

^{1.} Worst case, all digital inputs and outputs LOW.



System performance characteristics within specified operating conditions

				Temperature Range				
			Sta	ndard		ended	1	
Para	meter	Test Conditions	Min	Max	Min	Max	Units	
ELI	Linearity Error Integral, Independent	V _{RT} , V _{RB} - NOM		0.3		0.3	%	
EFD	Linearity Error Differential	V _{RT} , V _{RB}		0.3	İ	0.3	%	
a	Code Size	V _{RT} , V _{RB} - NOM	15	185	15	185	% Nominal	
EOT	Offset Error Top	V _{IN} - V _{RT}		35		45	mV	
E _{OB}	Offset Error Bottom	V _{IN} - V _{RB}		-22		-24	mV	
T _{CO}	Offset Error Temperature Coefficient			±50	1	±50	μV/°C	
BW	Bandwidth, Full Power Input		7	 	5		MHz	
tTR	Transient Response, Full Scale			20		20	ns	
SNR	Signal-to-Noise Ratio	10MHz Bandwidth		 		<u></u>		
		20MSPS Conversion Rate						
	Peak Signal/RMS Noise	1.248MHz Input	53		52		dB	
		2.438MHz Input	50		49		₫₿	
	RMS Signal/RMS Noise	1.248MHz Input	44		43		dB	
		2.438MHz Input	41		40		dB	
NPR	Noise Power Ratio	DC to 8MHz White Noise Bandwidth	36.5	<u> </u>	36.5		dB	
		4 Sigma Loading	1					
		1.248MHz Slot	ŀ					
		20MSPS Conversion Rate						
E _{AP}	Aperture Error			60		60	ps	
DP	Differential Phase	NTSC @ 4x Color Subcarrier		1.0	-	1.0	Degree	
DG	Differential Gain	NTSC @ 4x Color Subcarrier		1.7		1.7	%	



Output Coding (Input range from 0.000 to -2.000V)

	Binary	Offset Two's Complement		
Input Voltage	True	Inverted	True	Inverted
(-7.84 mV/Step)	NMINV - 1	0	0	1
	NLINV - 1	0	1	0
0.000	00000000	11111111	10000000	01111111
•	•	•	•	•
•	•	•	•	•
-0.0078	00000001	11111110	10000001	01111110
•	•	•	•	•
•	•	•	•	•
•	•	•	•	•
•	•	•	•	•
-0.9960	01111111	10000000	11111111	00000000
- 1.0039	10000000	01111111	00000000	11111111
•	•	•	•	•
•	•	•	•	•
•	•	•	•	•
•	•	•	•	•
-1.9921	11111110	00000001	01111110	10000001
•		•	•	•
•		•	•	•
-2.000	11111111	0000000	01111111	10000000

Calibration

To calibrate the TDC1007, the top of the reference resistor chain, R_T , is connected to analog ground. The reference voltage is then set up by adjusting the bottom of the resistor chain to -2.0V. When this technique is used, offset errors are generated by the inherent parasitic resistance between the package pin and the actual resistor chain on the A/D. These parasitic resistors are shown as R_1 and R_2 in the Functional Block Diagram. The offset voltage error is the result of the resistor chain current flowing through the parasitic resistance. These errors can be compensated for by applying an equal offset to the analog input signal or by adjusting the voltages on R_T and R_B .

The effect of the offset error at the bottom of the resistor chain manifests itself in the form of a slight gain error which can be compensated for by varying the voltage applied to R_B . This voltage will necessarily be more negative than the desired reference level of -2.0V. The actual operating range of the A/D converter will be:

(VAGND - (IBEE x R1)) to (VRB + (IREE x R2).

However, if both ends of the resistor chain are driven by transistor—buffered operational amplifiers, the voltages on R_T and R_B could then be adjusted to remove the effect of the parasitic resistances and therefore eliminate the need to apply a compensating offset voltage to the analog input signal. Here the operating range of the A/D will be:

Since both V_{RT} and V_{RB} are adjustable, the offset voltage error effect can be cancelled and the A/D operated with gain and offset errors removed.

The TDC1007 provides access to the mid-point of the reference resistor chain, R_M . This point can be sensed by external circuitry for temperature compensation or gain tracking functions in the system. It can also be driven in the manner shown in Figure 6 for fine linearity correction.

Typical Application

Figure 5 shows a typical interface circuit for a TDC1007, an input buffer amplifier, and the reference voltage source. The reference voltage is supplied by an inverting amplifier that has been buffered with a PNP transistor. The transistor sinks the current flowing through the reference resistor chain and keeps the driving impedance at the bottom end of the resistor chain low. The gain of the overall circuit is adjusted by varying the input voltage to the operational amplifier.

The input amplifier is a bipolar wideband operational amplifier followed by an NPN transistor buffer. The transistor drives the input capacitance of the A/D converter and keeps the overall circuit frequency stable. The offset error is compensated by varying the current into the summing junction of the op-amp. Note that all five V_{IN} points are connected together and the buffer amplifier feedback loop is closed at that point. The buffer amplifier has a gain of two, raising the $1V_{IN}$ points are converted together. The A/D converter operates with a $2V_{IN}$ full-scale.



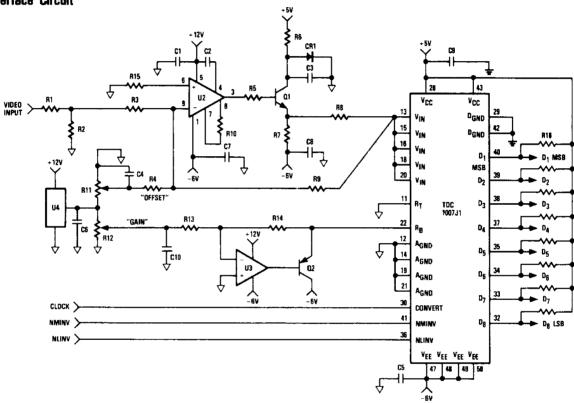
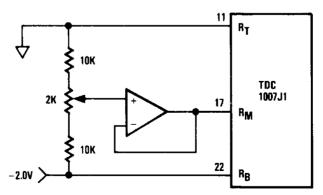


Figure 6. Method For Driving Mid-Point Of Resistor Chain



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Parts List

Resistors		Capacitors		Integrated Circuits				
R1	t	1/4W		C1	0.1 ₄ F	50V	UI	TDC1007J1
R2	t	1/4W		C2	• "	50V	U2	Plessey SL541C
R3	1K	1/4W	5%	C3	0.1µF	50V	U3	μ Α 741
R4	4.3K	1/4W	5%	C4	0.1µF	50V	U4	MC1403
R5	10	1/4W	5%	C5	0.1µF	50V		
R6	56	1/2W	5%	C6	1.0 <i>u</i> F	15V		
R7	240	2W	5%	C7	0.1uF	50V		
R8	6.8	1/2W	5%	C8	0.1µF	50V	Diode	S
R9	2K	1/2W	5%	C9	0.1µF	50V	CD1	1314001
R10	•	1/4W	5%	C10	0.1µF	50V	CR1	1N4001
R11	2K	1/4W	10-turn					
R12	2K	1/4W	10-turn					
R13	1.3K	1/4W	5%				Transistors	
R14	2.2K	1/4W	5%					
R15	680	1/4W	5%				Q 1	2N5836
R16	2.2K	SIP	5%				02	2N2907

[†] Indicates input terminator/divider

Ordering Information

Product Number	Temperature Range	Screening	Package	Package Marking
TDC1007C1F	EXT-T _C = -55°C to 125°C	Commercial	68 Contact Chip Carrier	1007C1F3
TDC1007C1A	EXT-T _C = -55°C to 125°C	High Reliability ¹	68 Contact Chip Carrier	1007C1A3
TDC1007J1C	STD-T _A = 0°C to 70°C	Commercial	64 Lead DIP	1007J1C3
TDC1007J1G	STD-TA - 0°C to 70°C	Commercial With Burn-In	64 Lead DIP	1007J1G3
TDC1007L1F	EXT-T _C = -55°C to 125°C	Commercial	68 Leaded Chip Carrier	1007L1F3
TDC1007L1A	EXT-T _C = -55°C to 125°C	High Reliability 1	68 Leaded Chip Carrier	1007L1A3

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Note:

^{*} Indicates amplifier compensation

^{1.} Per TRW document 70Z01757.